Application/Control No. Applicant(s)/Patent Under Reexamination NARUSAWA, HITOSHI Examiner Justin Michalski Applicant(s)/Patent Under Reexamination NARUSAWA, HITOSHI Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,353,671	03-2002	Kandel et al.	381/318
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	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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